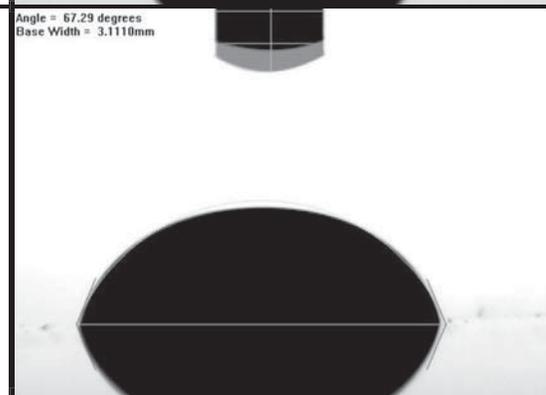
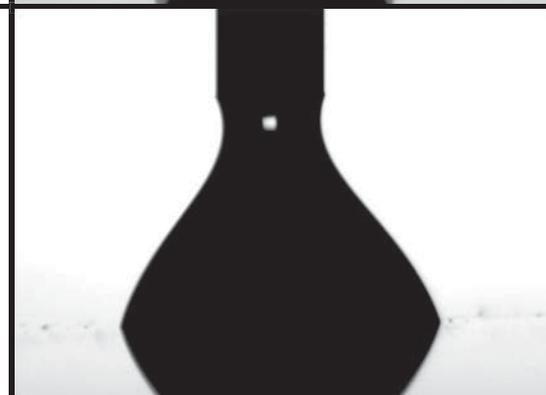
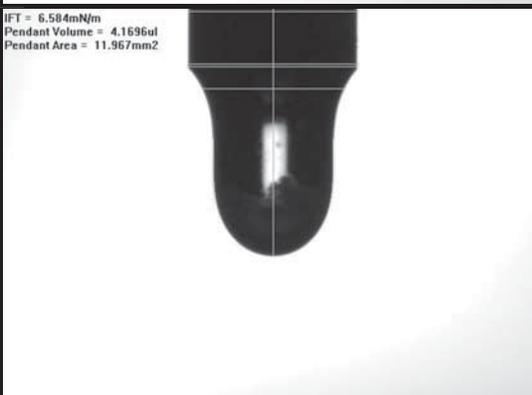
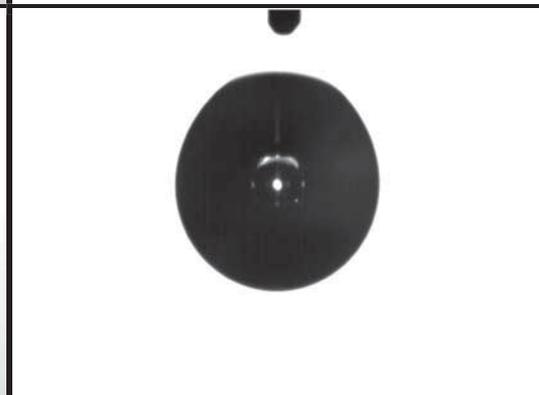
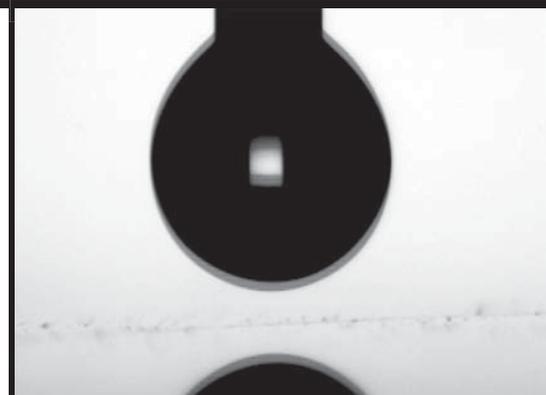


# First Ten Ångstroms™

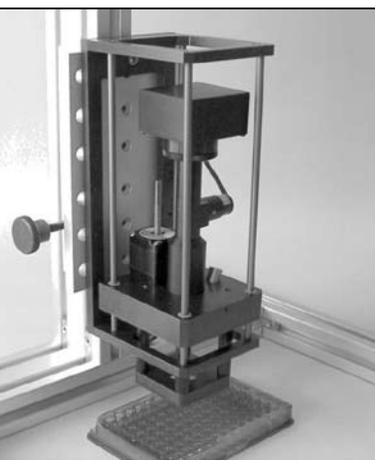
Dilational Stress to Low  $\gamma_{LV}$  (6 mN/m)

Drop Detachment at 250fps

Automated Touch-off



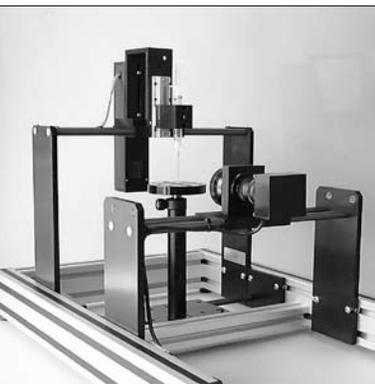
Surface Science Instruments with Real Vision™  
Product Line



### FTA1000 A Class

Special Purpose Dispense and Measurement Heads

- compact, modular, self-contained instruments
- mix-and-match controller, pumps, and heads
- heads can be located remotely on robotics
- provide contact angles and/or precision dispense
- all use small microscopes and cameras to verify dispense
  
- precision dispense of high-value picoliter and nanoliter drops
- jetting of heated polymers and solders
- top view contact angles for wells and low-angle surfaces
- classic side view contact angles
  
- OEM friendly (incorporate into your system)
- self-contained microprocessor: no host computer required
- built-in LCD and keypad
- supports local VGA, touchscreen, keyboard, mouse
- browser interface over Ethernet LAN or Internet



### FTA1000 B Class

Economical Drop Shape Instruments

- expandable, upgradeable instruments
- contact angle and surface tension measurements
  
- user-swappable modules for entire electronics chain
- plug and play determination of options present
- excellent for QA and factory floor use
- some systems can be powered by laptop
  
- To design your instrument:
  - 1 choose stage and/or chamber
  - 2 choose camera + microscope + backlight combination
  - 3 choose dispense pump + tip Z control
  
- 36 page catalog available to explain all options, or
- let your distributor or FTA recommend a configuration
- pre-configured *student* edition in stock for immediate delivery
  
- Vista® compatible when Firewire camera chosen
- can use most FTA200 stages and chambers
- instrument tilt stage available



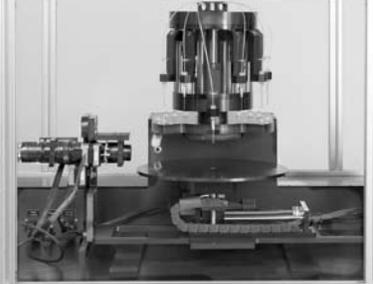
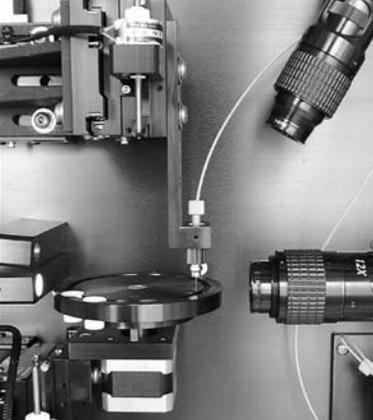
### FTA1000 C Class

General Purpose Laboratory Drop Shape Instruments

- top-of-the-line general purpose laboratory instrument
- very wide range of modules available
- all modules user-installable
- variety of additional stages and chambers planned for future
  
- To design your instrument:
  - 1 choose stage and/or chamber
  - 2 choose camera + microscope + backlight combination
  - 3 choose dispense pump + tip Z control

*steps 1-3 just like a B frame...*

  - 4 optionally add an autosampler
  - 5 optionally add a lookdown camera for locating drop on sample
  
- 1 and 4 pump options
- heated syringes possible
  
- all the flexibility of the B frame and more
- designed to be run by automation *one-click* scripts
- autosampler can support tip changer
- fixed mag, detented mag, and autozoom microscope options
- can interface to external hosts for robotic sample handler control

DCA-100	<ul style="list-style-type: none"> <li><input type="checkbox"/> economical force balance tensiometer</li> <li><input type="checkbox"/> meets ASTM and DIN measurement standards</li> </ul>	
Contact Angle Tensiometer	<ul style="list-style-type: none"> <li><input type="checkbox"/> choice of 100µg or 1µg sensitivities</li> <li><input type="checkbox"/> 100µg is robust and satisfactory for ring and plate IFT</li> <li><input type="checkbox"/> 1µg provides sensitivity for 10µm fiber contact angles</li> <li><input type="checkbox"/> advancing / receding contact angles by Wilhelmy immersion</li> <li><input type="checkbox"/> calculates surface energies from contact angles</li>   <li><input type="checkbox"/> surface and interfacial tensions: liquid-vapor or liquid-liquid</li> <li><input type="checkbox"/> ring or plate methods</li> <li><input type="checkbox"/> critical micelle determination</li> <li><input type="checkbox"/> temperature probe for liquid</li> <li><input type="checkbox"/> density measurement</li> <li><input type="checkbox"/> disposable paper plates for liquid-vapor surface tension</li> <li><input type="checkbox"/> rod method for liquid-vapor surface tension</li> </ul>	
FTA2000	<ul style="list-style-type: none"> <li><input type="checkbox"/> 300mm wafer capable platter</li> <li><input type="checkbox"/> can handle smaller wafers</li> <li><input type="checkbox"/> can handle rectangular samples that fit within 300mm circle</li> </ul>	
Wafer Analyzer	<ul style="list-style-type: none"> <li><input type="checkbox"/> contact angle and surface tension analysis</li> <li><input type="checkbox"/> platter and camera tilt through 90° for receding angle analysis</li> <li><input type="checkbox"/> 6 tip, 17 liquid vial, autosampler</li> <li><input type="checkbox"/> tip changer option available</li>   <li><input type="checkbox"/> fully enclosed</li> <li><input type="checkbox"/> clean room compatible</li> <li><input type="checkbox"/> temperature stabilized to 40C</li>   <li><input type="checkbox"/> autofocus, autozoom microscope</li> <li><input type="checkbox"/> adjustable lookdown angle</li>   <li><input type="checkbox"/> script programmable for unattended operation</li> <li><input type="checkbox"/> macros to automate drop formation and baseline determination</li> <li><input type="checkbox"/> host computer interface to coordinate sample loading</li> <li><input type="checkbox"/> SECS interface available</li> </ul>	
FTA4000	<ul style="list-style-type: none"> <li><input type="checkbox"/> piezo-electric jetting for picoliter drops</li> <li><input type="checkbox"/> jetted volumes down to 20 picoliters</li> <li><input type="checkbox"/> can also form classical pendant drops up to µl volumes</li> <li><input type="checkbox"/> automated touch-off for classical drops</li> <li><input type="checkbox"/> dip-and-sip for low volume pump prime</li> </ul>	
Small Drop Contact Angle Analyzer	<ul style="list-style-type: none"> <li><input type="checkbox"/> two camera design: horizontal analytical and lookdown locator</li> <li><input type="checkbox"/> zoom microscopes on both axes</li> <li><input type="checkbox"/> all optics mount on single surface plate for stability</li> <li><input type="checkbox"/> two halogen illuminators adjustable for best image contrast</li> <li><input type="checkbox"/> enclosed cabinet for stability</li> <li><input type="checkbox"/> X-Y-Z-θ automated specimen stage</li> <li><input type="checkbox"/> special analysis software for rapid absorption work</li> </ul>	
Legacy Instruments	<p>The following instruments have been replaced by the FTA1000:</p> <p>FTA125, FTA135, FTA136, FTA137, FTA188, FTA200</p>	
	<p>If you need one of these units, say to match a setup at another facility, they can be obtained by special order. There will be a lead time and the price will reflect a custom order charge.</p>	

## Useful Formulas

<p><b>Young's Equation</b> Contact angle of liquid on surface Also, the force balance on a spherical sessile drop</p> $\gamma_{SV} - \gamma_{SL} = \gamma_{LV} \cos \theta$ <p><math>\gamma_{SV}</math> = solid vapor IFT (aka <i>surface energy</i> of solid)  <math>\gamma_{SL}</math> = solid liquid IFT (IFT = interfacial tension)  <math>\gamma_{LV}</math> = liquid vapor IFT (aka <i>surface tension</i> of liquid)  <math>\theta</math> = contact angle of drop (angle in liquid at three-phase line)</p>	<p><b>Laplace Pressure across Curved Surface</b></p> $\Delta P = \gamma_{LV} (1/R_1 + 1/R_2)$ <p><math>\Delta P = \perp</math> pressure differential across interface  <math>R_1, R_2</math> = principal radii of curvature of interface at <math>\perp</math> point  for sphere, <math>R_1 = R_2</math> = radius of sphere</p>
<p><b>Spherical Drop Geometry</b></p> $\theta = 2 \arctan(2h / d)$ <p>h = height of drop  d = diameter of drop's wetted surface on solid  <math>\theta</math> = contact angle of drop</p>	<p><b>Laplace-Young Equation</b> IFT of liquid-vapor (<math>\gamma_{LV}</math>) or liquid-liquid (<math>\gamma_{LL}</math>) interface</p> $mgh = \Delta P = \gamma_{LV} (1/R_1 + 1/R_2)$ <p>m = density differential across interface  g = acceleration of gravity  h = vertical position with drop, measured from apex</p>
<p><b>Force on Wilhelmy Plate</b></p> $F = L \gamma_{LV} \cos \theta$ <p>F = force on plate  L = wetted perimeter length</p>	<p><b>Force - Mass (Weight) Relationship</b></p> $F = mg$ <p>F = force (in Newtons) measured by balance  m = mass (in kilograms)  g = acceleration of gravity, nominally 9.8m/s<sup>2</sup>  e.g. 1 gram mass → 9.8 milli Newton force</p>
<p><b>Basic Statistics</b></p> $\mu = \sum x_i / n$ $\sigma = \sqrt{\{ 1/(n-1) \sum (x_i - \mu)^2 \}}$ $COV = \sigma / \mu$ <p>n = number of items  i = index of item (for summations)  <math>x_i</math> = value of i<sup>th</sup> item  <math>\mu</math> = mean value (aka <i>average</i>) of set  <math>\sigma</math> = standard deviation of set  COV = coefficient of variance</p>	<p><b>Hook's Law and Dilational Stress</b></p> $\tau = G \gamma$ $\tau(t) = G(t) \gamma(t)$ $G' = \tau_0 \cos(\phi) / \gamma_0$ $G'' = \tau_0 \sin(\phi) / \gamma_0$ $\eta' = G'' / \omega$ $\eta'' = G' / \omega$ <p><math>\tau</math> = stress, or force per unit area  <math>\tau(t)</math> = time varying stress, typically <math>\tau_0 \sin(\omega t)</math>  G, G(t) = elastic modulus  <math>\gamma</math> = strain, relative change in length (or shape)  <math>\gamma(t)</math> = time varying strain, typically <math>\gamma_0 \sin(\omega t + \phi)</math>  G' = in-phase <i>elastic</i> modulus  G'' = out-of-phase <i>viscous</i> modulus  <math>\eta'</math> = dynamic viscosity  <math>\eta''</math> = dynamic elasticity</p>
<p><b>Wetting Tension</b> Characterizes solid surface by RHS of Young's equation:</p> $WT = \gamma_{LV} \cos \theta$ <p>Note this varies from <math>-\gamma_{LV}</math> (at 180°) to <math>+\gamma_{LV}</math> (at 0°)</p>	<p><b>Zisman's Critical Wetting Tension</b></p> <p>Critical Wetting Tension (CWT) is defined as intersection of IFT-cos <math>\theta</math> plot line with cos 0° (IFT on X axis, cos <math>\theta</math> on Y). IFT at this point is CWT. Experimentally it is found <math>CWT \approx \gamma_{SV}</math></p>
<p><b>Girifalco-Good-Fowkes-Young Rule</b> Uses the combining rule <math>\gamma_{SL} = (\sqrt{\gamma_{SV}} - \sqrt{\gamma_{LV}})^2</math></p> $1 + \cos \theta = 2 \sqrt{(\gamma_{SV} / \gamma_{LV})} - \pi / \gamma_{LV}$ <p><math>\pi</math> = spreading pressure (often <math>\approx 0</math>)</p>	<p><b>Owens-Wendt Geometric Mean Mean</b></p> $(1 + \cos \theta) \gamma_{LV} = 2 \sqrt{(\gamma_{SV}^D \gamma_{LV}^D)} + 2 \sqrt{(\gamma_{SV}^P \gamma_{LV}^P)}$ <p>D superscript indicates dispersive and P polar component</p>
<p><b>Wu's Harmonic Mean Rule</b></p> $(1 + \cos \theta) \gamma_{LV} = 4 \{ \gamma_{SV}^D \gamma_{LV}^D / (\gamma_{SV}^D + \gamma_{LV}^D) + \gamma_{SV}^P \gamma_{LV}^P / (\gamma_{SV}^P + \gamma_{LV}^P) \}$	<p><b>Lewis Acid/Base Rule</b></p> $(1 + \cos \theta) \gamma_{LV} = 2 \sqrt{(\gamma_{SV}^D \gamma_{LV}^D)} + 2 \sqrt{(\gamma_{SV}^A \gamma_{LV}^B)} + 2 \sqrt{(\gamma_{SV}^B \gamma_{LV}^A)}$ <p>A superscript indicates acid and B base component</p>
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